## Notice of References Cited Application/Control No. 10/618,494 Examiner Paul Kim Applicant(s)/Patent Under Reexamination OWEN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0024812	02-2004	Park et al.	709/203
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